Data Sets Used in Statistical Methods for Reliability Data

Second Edition

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This collection contains csv files for the data sets used in the examples and exercises of Meeker, Escobar, and Pascual (2021) (hereafter SMRD2). For each dataset, this document describes the original source (if it appeared in the literature before appearing in SMRD1 or SMRD2), provides some background for the data set, and points to where it is used in SMRD2.

These data sets are archived and publicly available on DataShare, Iowa State University's open data repository, and can be accessed at:

https://doi.org/10.25380/iastate.c.5395665.
The data files and this document are also available from

https://github.com/wqmeeker/SMRD2Data.git

and at the SMRD2 webpage

https://www.wiley.com\go\meeker\reliability2e.

A. Laboratory Failure-Time and Single-Time Strength Data

1. AlloyA.csv

This file contains data on fatigue crack length as a function of number of cycles. These data were obtained visually from Figure 4.5.2 in Bogdanoff and Kozin (1985, page 242). These data were analyzed in Lu and Meeker (1993) and are used in SMRD2 Example 1.10 and Sections 21.1–21.3.

2. AlloyC.csv

These data are from an experiment to measure long transverse tensile strength (ksi) of a 7475-T651 aluminum plate (0.5–1.0 inch thick) and are used in SMRD2 Section 11.6.

3. AlloyT7987.csv

This file contains fatigue lives of 67 specimens of Alloy T7987. There were also five specimens that were tested to 300 thousand cycles but that did not fail. These data are used in SMRD2 Sections 6.4, 11.6, and Exercise 11.17.

4. ApplianceB.csv

This file contains use-rate accelerated test data presented in Meeker, Escobar, and Hong (2009) and used in SMRD2 Example 1.6.

5. ApplianceCord.csv

This file contains data from a life test electric cords for a small appliance. The purpose of the test was to compare a standard cord with a less expensive alternative. These data were first given in Nelson (1982, page 121) and used in SMRD2 Exercise 12.10.

6. BearingA.csv

These data are results of a small bench test of a roller bearing with three early failures (defective units). These data first appeared in Genschel and Meeker (2010) and are used in SMRD2 Example 8.17.

7. Berkson10220.csv

This file contains interval-censored data for 10,220 times between Americium-241 α -particle arrivals. These data originally appeared in Berkson (1966) and are used in SMRD2 Sections 7.1–7.6.

8. Berkson200.csv

This file contains a random sample of size 200 from Berkson10220.csv. These data are used in SMRD2 Sections 7.1–7.6.

9. BKfatigue10.csv

This file contains fatigue-failure data from Bogdanoff and Kozin (1985, pages 224–225) and they are used in SMRD2 Example 11.3.

10. Bulb.csv

This file contains incandescent light bulb life-test data from Davis (1952) and used in SMRD2 Exercise 6.14.

11. CeramicBearing02.csv

This file contains life test results on rolling contact fatigue of ceramic ball bearings given by McCool (1980) and are used in SMRD2 Exercise 17.3.

12. ChainLink.csv

This file contains the results of a load-controlled high-cycle fatigue test conducted on chain links from Parida (1991) and used in SMRD2 Exercises 3.6, 6.8, and 8.3.

13. CircuitPack05.csv

This file contains data from a life test data conducted to compare the failure-time distributions of circuit packs manufactured by two different vendors. These data were first reported by Hooper and Amster (1998, Table 9.2) and are used in SMRD2 Exercise 12.9.

14. ConnectionStrength.csv

This file contains data on breaking strength of 20 wire connections given in Nelson (1982, page 348) and used in SMRD2 Exercise 16.6.

15. ConnectorStress.csv and ConnectorStrength.csv

These files contain stress-strength data from Liu and Abeyratne (2019, Section 6.2) and are used in SMRD2 Section 23.2.2.

16. DetonatorSensitivity.csv

This file contains test data to estimate a detonator's sensitivity (probability of detonating as a function of voltage) and were first reported in Dror and Steinberg (2008). These data are used in SMRD2 Exercise 8.28.

17. DeviceA.csv

These data are from an accelerated life test for an electronic device from Hooper and Amster (1998, Table 9.3) and used in SMRD2 Sections 18.3 and 18.4 and Exercises 18.7–18.9, 18.14, and 18.17.

18. DeviceC.csv

These data are from am accelerated life test of an integrated circuit device and are used in SMRD2 Exercise 18.3.

19. HeaterComparison.csv

These data come from an accelerated life test comparing two suppliers of tubular heaters used in ovens and are used in SMRD2 Exercise 12.12.

20. HypoidPinionGear.csv

These data come from an accelerated life test to estimate the relationship between fatigue life and torque and are used in SMRD2 Exercise 18.28.

21. ICData.csv

This file contains the results of an accelerated life test, conducted at one level of elevated temperature, to study an electromigration-related failure mode. These data are used in SMRD2 Exercises 8.5 and 18.25.

22. InkjetPenA.csv

These data are from a life test of an inkjet pen, comparing two different ink formulations and are used in SMRD2 Example 12.14.

23. InkjetPrintheadB.csv

This file contains data from a life test of an inkjet printhead that resulted in two failure modes and is used in SMRD2 Exercise 16.9.

24. JEP118.csv

These interval-censored data come from an accelerated life test for an electronic device from Whitman (2003) and used as SMRD2 Exercise 19.1.

25. KevlarWrappedPressureVessels.csv

This file contains accelerated life test data originally from Gerstle and Kunz (1983), but re-analyzed in many other places, including Section 23.4 of SMRD2.

26. LaminatePanel.csv

This file contains data on the fatigue life of panel specimens tested at four different levels of stress that were analyzed in Shimokawa and Hamaguchi (1987) and Pascual and Meeker (1999). These data are analyzed in SMRD2 Section 17.6.

27. LEDLife.csv

This file contains pseudo failure times derived from the LED-A accelerated repeated measures degradation data in LED.A.full.csv. These data were first analyzed in Pascual, Meeker, and Escobar (2006) and also studied in SMRD2 Section 21.7.

28. LEDLifeSubset.csv

These accelerated life-test data were derived from LEDLife.csv by excluding data from a different failure mode at 130°C and 40 mA. These data were first analyzed in Pascual et al. (2006) and also studied in SMRD2 Section 21.7.

29. LFP1370.csv

These limited-failure-population accelerated life test data were first analyzed in Meeker (1987) and are used in SMRD2 Examples 1.2 and 3.7, Section 11.5, and Exercise 11.3.

30. LZbearing.csv

These data, from fatigue endurance tests, were first given in Lieblein and Zelen (1956) and were analyzed in Lawless (1982) and SMRD1. The data are used in SMRD2 Section 3.4, Examples 1.1, 8.3, and 11.1, and Exercise 3.1.

31. MechanicalSwitch.csv

This file contains competing-risk failure-time data, with two failure modes, on mechanical switches are from Nair (1984) and are used in SMRD2 Exercise 16.8.

32. MetalWear.csv

These data are from sliding-metal wear tests to study the wear resistance of a metal alloy and used in SMRD2 Example 11.1 and Exercises 21.13 and 21.15.

33. Mylarpoly.csv

These data, given in Kalkanis and Rosso (1989), were from an accelerated life test of a Mylar-polyurethane insulating structure and are used in Section 18.5 and Exercises 18.22 and 18.23 in SMRD2.

34. NewSpring.csv

These data were obtained from a factorial accelerated life test experiment to study the relationship between spring lifetimes and processing temperature, amount of displacement in the spring test (stroke), and processing method. The data were first used in Meeker, Escobar, and Zayac (2003) to illustrate a sensitivity analysis and is used in SMRD2 Section 19.3 and Exercise 19.17.

35. NewTechnology.csv

These data are from a temperature-accelerated life test on an IC device and is presented or used in SMRD2 Section 19.1, Exercises 19.4, 19.6, and 19.7.

36. NiCdBattery.csv

These accelerated test data on rechargeable nickel-cadmium battery cells were presented in Brown and Mains (1979) and used in SMRD2 Example 1.9 and Exercise 19.16.

37. PartA.csv

These data data are from an experiment to compare three operators who performed life tests on a component in a cutting tool and are used in SMRD2 Example 12.2, Sections 12.2 and 12.5, and Exercises 12.7 and 12.8.

38. PhotoDetector.csv

These data, reported by Weis, Caldararu, Snyder, and Croitoru (1986), were from a life test on silicon photodiode detectors and used in SMRD2 Exercises 3.12 and 6.9.

39. PrintedCircuitBoard.csv

These data, given in Meeker and LuValle (1995), were from humidity-accelerated life test of printed circuit boards and are used in SMRD2 Example 1.8 and Exercise 1.11.

40. Snubber.csv

These data, first given in Nelson (1981), were obtained from an accelerated test comparing two toaster snubber designs. The data are used in SMRD2 Examples 12.1, 12.3, 12.5, 12.6, 12.7, 12.8, 12.9, and 12.10 and Exercises 12.3, 12.4, and 12.5.

41. SuperAlloy.csv

This data set, given in Nelson (1984) and Nelson (2004), contains fatigue lifetest results from a strain-controlled test of a nickel-base superalloy. The data are used in Examples 17.7, 17.8, 17.9, and 17.10 and Exercises 17.9 and 17.12.

42. Tantalum.csv

These data, from Singpurwalla, Castellino, and Goldschen (1975), resulted from a temperature- and voltage-accelerated life test of tantalum capacitors and are used in SMRD2 Exercise 19.15.

43. TireDataSet.csv

These data, given in Krivtsov, Tananko, and Davis (2002), were from an experiment that was designed to reproduce automobile tire failures that had been seen in the field. They are use in SMRD2 Exercise 17.5.

44. Titanium01.csv

These data were obtained from a fatigue test of titanium alloy specimens and are used in SMRD2 Exercise 6.7.

45. Transistor.csv

These data, given in Wilk, Gnanadesikan, and Huyett (1962), were from an accelerated test of transistors and are used in SMRD2 Exercise 6.5.

46. TurbineDevice.csv

These data were from a life test of a newly designed turbine device and are used in SMRD2 Exercise 16.7.

47. ZelenCap.csv

These data were obtained from a factorial experiment to study the effect that voltage and temperature have on capacitor lifetime. The data were first analyzed in Zelen (1959) and used in SMRD2 Examples 17.15 and 17.16 and Exercises 17.16 and 17.20.

48. ZelenCapSub.csv

These data are a subset of ZelenCap.csv with the bad data at 180C and 200 volts removed. They are used in SMRD2 Example 17.17.

B. Field Failure-time Data

1. ApplianceBField.csv

This file contains failure-time data obtained from warranty return information. These data were first presented in Meeker et al. (2009) and are used in SMRD2 Exercise 16.10.

2. Backblaze1Q2016.csv

This file contains Backblaze disk drive failure data as of 1Q2016 and used in Mittman, Lewis-Beck, and Meeker (2019).

3. BackblazeDrive14.csv

Subset of Backblaze1Q2016.csv containing drive model 14 and used in SMRD2 Section 23.1.

4. BearingCage.csv

This file contains bearing-cage field-failure data consisting of fracture times for failed units and running times for units that have not failed. These data were abstracted from Abernethy, Breneman, Medlin, and Reinman (1983) and they are used in SMRD2 Example 8.18, Exercise 8.27, Section 10.2, Examples 10.8 and 10.9, and Section 15.7.

5. BleedSystem.csv

This file contains failure and running times for 2256 aircraft engine bleed systems. These data were abstracted from Abernethy et al. (1983) and are used in SMRD2 Example 6.5 and Exercise 8.20.

6. BondStrength.csv

Failures in a microelectronic device were caused by weakened wire bonds. The data are from devices in three separate manufacturing batches and they are used in SMRD2 Exercise 12.13.

7. CircuitPack04.csv

This file contains interval-censored field tracking data for circuit packs in a telecommunications system. The data were first reported by Hooper and Amster (1998, Table 9.1) and are used in SMRD2 Exercise 8.23.

8. CircuitPack06.csv

This file contains data giving the number of failures observed during periodic inspections in a field trial of early production circuit packs and used in SMRD2 Examples 1.7, and 11.8.

9. ComponentA.csv

This file contains data giving number of failures of a component type that is used numerous times in a large electronic system and are used in SMRD2 Exercises 7.4 and 8.6.

10. ComponentB.csv

This file contains failure-free running times for early production metal components that had been introduced into service over time. The data are used in SMRD2 Example 8.17.

11. CompTime.csv

This file contains the times to complete a computing task at a centralized computer service at Louisiana State University and used in SMRD2 Sections 17.1–17.3.

12. DetonatorA.csv

This file contains shelf-life data for explosive detonators manufactured in 14 different batches. A component of the detonator was tested destructively and graded as pass or fail. The data are used in SMRD2 Exercise 12.11.

13. DeviceG.csv

These data are from a field-tracking study of an electro-mechanical subsystem that had two failure modes and are used in Sections 16.1, 16.3, 16.4, and 16.6 and in Exercises 16.2–16.4 in SMRD2.

14. DeviceG-sim-pseudo-joint-dependent.csv

This file contains joint pseudo data derived from the DeviceG data under a strong dependence assumption and is used in Section 16.6 in SMRD2.

15. DeviceG-sim-pseudo-joint-independent.csv

This file contains joint pseudo data derived from the DeviceG data under an independence assumption and is used in Section 16.6 in SMRD2.

16. DeviceH.csv

This file contains field-failure data for an electro-mechanical device that were first presented in Doganaksoy, Hahn, and Meeker (2000). They are used in Exercises 6.15 and 10.17 in SMRD2.

17. DeviceJ40.csv, DeviceJ55.csv, DeviceJ69.csv

These files contain field-failure data where a small proportion of units had failed at data-freeze dates 40, 55, and 69 months after introduction of units to the field. These data are used in Section 23.3 of SMRD2.

18. DeviceN.csv

This file contains current-status warranty-replacement data for a component in a larger product. The data are used in SMRD2 Exercises 8.25 and 15.15.

19. ElectronicSystem.csv

This file contains failure data on devices in electronic systems that have been deployed in Earth orbit. The data are used in SMRD2 Exercise 3.8.

20. Fan.csv

This file contains diesel generator fan-failure data from Nelson (1982, page 133) and are used in SMRD2 Examples 1.3, 7.13, 11.2, and 11.19.

21. HeatExchanger.csv

These data are from nuclear power plant heat exchangers and are used in SMRD2 Examples 1.4, 3.2, 3.8, and Exercises 8.1, 8.2, and 10.16.

22. MotorA.csv

This file contains field-failure data of a motor that is part of a larger system and is used in SMRD2 Exercises 11.6 and 15.15.

23. ProductE.csv

The data were derived from warranty returns of a product subjected to 19 different failure modes and are used in SMRD2 Sections 16.4 and 16.5 and Exercises 16.5, 16.17, 16.18, and 16.19.

24. RocketMotor.csv

The data were from a field-performance assessment of rocket motors, installed in missiles, that failed due to thermal cycling. The data were given in Olwell and Sorell (2001) and used in SMRD2 Section 10.5.

25. ShockAbsorber.csv

This file contains failure times (in kilometers driven) of vehicle shock absorbers and were reported in O'Connor (1985). The data are used in SMRD2 Sections 8.2, 8.3, 9.3, and 9.4, Examples 3.10, 3.11, 3.12, 6.2, 8.1, 8.2, 9.10, and 9.11 and Exercise 8.13

26. TurbineWheel.csv

Nelson (1982) presented these current status data from a study to estimate the time-to-crack initiation in turbine wheels. They are used in SMRD2 Examples 1.5, 3.14, and 6.4 and Exercise 1.9.

C. Destructive Degradation Data

1. AdhesiveBondA.csv

These adhesive bond strength data came from a destructive degradation test on units that had been in service for different amounts of time. The data are used in SMRD2 Sections 20.4–20.5.

2. AdhesiveBondB.csv

These data are from an accelerated destructive degradation test to estimate the failure-time distribution of an adhesive bond. The data were first given in Escobar, Meeker, Kugler, and Kramer (2003) and are used in SMRD2 Sections 20.4–24.9.

3. AdhesiveFormulationK.csv

These data are from an accelerated destructive degradation test to estimate the failure-time distribution of an adhesive. The data were first given in Xie, King, Hong, and Yang (2018) and are used in SMRD2 Section 20.10.

4. InsulationBreakdown.csv

This file contains accelerated destructive degradation data first used in Nelson (2004, page 535) and used in SMRD2 Exercise 20.11.

D. Repeated Measured Degradation Data

(a) DiskBer.csv

These data come from an accelerated repeated measured degradation test to study block error rates (the ratio of number of bytes with errors to the total number of bytes tested) of magneto-optic data storage disks. The data first appeared in Murray (1993) and are used in SMRD2 Exercise 21.6.

(b) GaAsLaser.csv

This file contains data from a GaAs Laser accelerated repeated measures degradation test and are used in SMRD2 Example 20.2 and Exercise 21.24.

(c) LED-Azerostart.csv

This file contains accelerated repeated measures degradation test data on an LED. These data are used in SMRD2 Section 21.15.

(d) LED-Afull.csv

The accelerated repeated measures degradation test data in this file were derived from LED.A.zero.start.csv by eliminating readings before 138 hours and renormalizing the data at 138 hours. These data are used in SMRD2 Section 21.15.

(e) LED-Asubset.csv

The repeated measures degradation test data in this file were derived from LED.A.Life.csv by excluding data from a different failure mode at 130°C and 40 mA. These data are used in SMRD2 Section 21.15.

(f) Resistor.csv

These data, given in Suzuki, Maki, and Yokogawa (1993), were from a temperature-accelerated repeated-measures degradation test of carbon-film resistors and are used in SMRD2 Exercise 21.12.

(g) DeviceB.csv

These data came from an accelerated repeated measured degradation test of a solid-state RF power amplifier and were first used in Meeker, Escobar, and Lu (1998). The data are used in SMRD2 Sections 21.5–21.6 and Exercise 21.19.

E. Recurrent Events Data

(a) AutomaticTransmission.csv

This file contains automatic transmission recurrent events data given in Nelson (2003, Table 1.1) and used in SMRD2 Exercise 22.8.

(b) BrakingGrids.csv

These are recurrent events data from two batches of locomotive braking grids, first presented in Doganaksov and Nelson (1998) and used in SMRD Section 22.3.

(c) ComputerLab.csv

This file contains computer lab maintenance recurrent events data used in SMRD2 Exercise 22.1.

(d) Cylinder.csv

This file contains locomotive engine cylinder replacement recurrent events data from Nelson and Doganaksoy (1989) and used in SMRD2 Section 22.2.3.

(e) MachineH.csv

These recurrent events data are cam from preventive maintenance records for a company's earth-moving machines and are studied in SMRD2 Example 22.5.

(f) SystemE.csv

This file contains recurrent events data from an electronic system with three different event types. These data are used in SMRD2 Exercises 22.8 and 22.9.

(g) ValveSeat.csv

These recurrent events data on the replacement of locomotive engine valve seats first appeared in Nelson (1995, 2003). They are used in SMRD2 Examples 22.1 and 22.2.

(h) WorkStation.csv

This file contains recurrent events data giving computer work station trouble reports. They are used in SMRD2 Exercise 16.1.

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